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Application Serial No.: 10/619,567

Yasuji HIRAMATSU, et al.

IN THE CLAIMS

Please amend the claims as follows:

- 1-4. (Canceled)
- 5. (New) A ceramic heater comprising a ceramic substrate in a disc form having a resistance heating element formed inside thereof or on the surface thereof, wherein said ceramic substrate has a straight notch.
- 6. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate has plural straight notches.
- 7. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate has an electrostatic electrode formed inside thereof; and functions as an electrostatic chuck.
- 8. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate has a through hole into which a lifter pin is inserted.
- (New) The ceramic heater according to Claim 5, wherein said ceramic substrate comprises a nitride ceramic or a carbide ceramic.
- 10. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate has a thickness of 20 mm or less.
- 11. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate has a diameter of 250 mm or more.
- 12. (New) The ceramic heater according to Claim 6, wherein said straight notches are evenly formed at a circumferential rim portion of said ceramic substrate.
- 13. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate is prevented from rotating by a contact of said notch with a rotation-blocking pin.

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- 14. (New) The ceramic heater according to Claim 5, wherein said ceramic substrate fitted into a supporting case and a rotation-blocking pin is inserted into said supporting case.
- 15. (New) A ceramic substrate having a conductor layer formed inside thereof or on the surface thereof,

wherein said ceramic substrate has a notch,

a chuck top conductor layer on the surface thereof, a guard electrode and/or a ground electrode inside thereof; and

said ceramic substrate functions as a wafer prober.

- 16. (New) The ceramic substrate according to Claim 15, wherein said ceramic substrate has a through hole into which a lifter pin is inserted.
- 17. (New) The ceramic substrate according to Claim 15, wherein said ceramic substrate comprises a nitride ceramic or a carbide ceramic.
- 18. (New) The ceramic substrate according to Claim 15, wherein said ceramic substrate has a thickness of 20 mm or less.
- 19. (New) The ceramic substrate according to Claim 15, wherein said ceramic substrate has a diameter of 250 mm or more.